Description

SUPERFET II MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate. Consequently, SUPERFET II MOSFET is very suitable for the various power system for miniaturization and higher efficiency. SUPERFET II FRFET MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

Features

- 700 V @ T_J = 150°C
- R_{DS(on)} = 220 mΩ (Typ.)
- Ultra Low Gate Charge (Typ. Q_g = 46 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 223 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

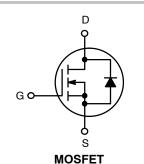
- Computing / Display Power Supplies
- Telecom / Server Power Supplies
- Industrial Power Supplies
- Lighting / Charger / Adapter

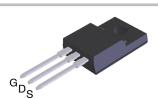


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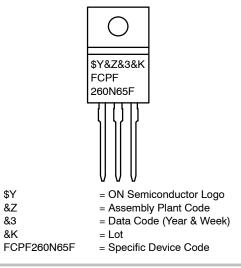
V _{DSS}	R _{DS(ON)} MAX	I _D MAX	
650 V	260 m Ω @ 10 V	15 A	





TO-220F Ultra Narrow Lead CASE 221BN

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Parameter	Value	Unit	
V _{DSS}	Drain to Source Voltage		650	V
V _{GSS}	Gate to Source Voltage	– DC	±20	V
		– AC (f > 1 Hz)	±30	
I _D	Drain Current	– Continuous (T _C = 25°C)	15	А
		– Continuous (T _C = 100°C)	9.5	
I _{DM}	Drain Current	– Pulsed (Note 1)	45	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		293	mJ
I _{AS}	Avalanche Current (Note 2)		3	А
E _{AR}	Repetitive Avalanche Energy (Note 1)		0.36	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)		50	
P _D	Power Dissipation	(T _C = 25°C)	36	W
		– Derate Above 25°C	0.29	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		–55 to +150	°C
ΤL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse width limited by maximum junction temperature. 2. $I_{AS} = 3 \text{ A}, R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 3. $I_{SD} \le 7.5 \text{ A}, \text{ di/dt} \le 200 \text{ A/}\mu\text{s}, \text{V}_{DD} \le 380 \text{ V}, \text{ starting } T_J = 25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	$R_{\theta JC}$ Thermal Resistance, Junction to Case, Max.		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	°C/W

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
FCPF260N65FL1-F154	FCPF260N65F	TO-220F (Pb-Free)	50 Units / Tube

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I _D = 10 mA, T _J = 25°C	650	-	-	V
		V_{GS} = 0 V, I_{D} = 10 mA, T_{J} = 150°C	700	-	-	V
$\Delta \text{BV}_{\text{DSS}}$ / $\Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 10 mA, Referenced to 25°C	-	0.72	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	10	μA
		V_{DS} = 520 V, V_{GS} = 0 V, T_{C} = 125°C	-	40	-	
I _{GSS}	Gate to Source Leakage Current	V_{GS} = ± 20 V, V_{DS} = 0 V	-	-	±100	nA
ON CHARACTE	RISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 1.5 \text{ mA}$	3	-	5	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 7.5 A	-	220	260	mΩ
9 _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 7.5 A	-	14.2	-	S
OYNAMIC CHA	RACTERISTICS	·				
C _{iss}	Input Capacitance	V_{DS} = 100 V, V_{GS} = 0 V, f = 1 MHz	-	1760	2340	pF
C _{oss}	Output Capacitance	1	-	59	80	pF
C _{rss}	Reverse Transfer Capacitance	1	-	1.0	-	pF
Coss	Output Capacitance	V_{DS} = 380 V, V_{GS} = 0 V, f = 1 MHz	-	34	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	223	-	pF
Q _{g(tot)}	Total Gate Charge at 10 V	V_{DS} = 380 V, I_{D} = 7.5 A, V_{GS} = 10 V	-	46	60	nC
Q _{gs}	Gate to Source Gate Charge	(Note 4)	-	9.6	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	1	-	20	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.52	-	Ω
WITCHING CH	ARACTERISTICS	·				
t _{d(on)}	Turn-On Delay Time	V_{DD} = 380 V, I_{D} = 7.5 A, V_{GS} = 10 V,	-	21.7	54	ns
t _r	Turn-On Rise Time	R _g = 4.7 Ω (Note 4)	-	10.5	32	ns
t _{d(off)}	Turn-Off Delay Time		-	54	118	ns
t _f	Turn-Off Fall Time	1	-	5.8	22	ns
OURCE-DRAI	N DIODE CHARACTERISTICS	•				
I _S	Maximum Continuous Source to Drain Diode Forward Current		-	_	15	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current		_	-	45	Α
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_{SD} = 7.5 A$	-	_	1.2	V
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 7.5 A,	-	98	-	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100 A/µs	_	450	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.4. Essentially independent of operating temperature.

TYPICAL PERFORMANCE CHARACTERISTICS

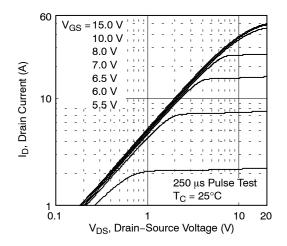
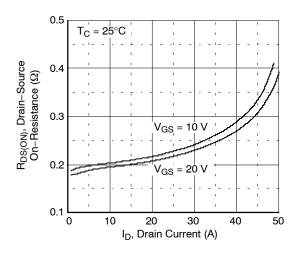
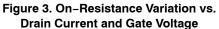


Figure 1. On-Region Characteristics





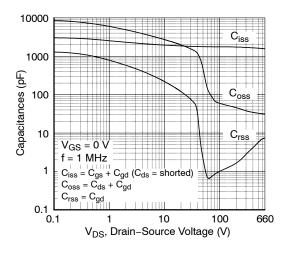


Figure 5. Capacitance Characteristics

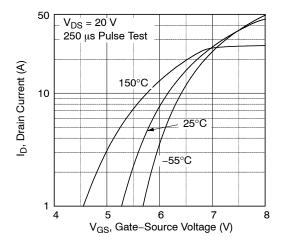


Figure 2. Transfer Characteristics

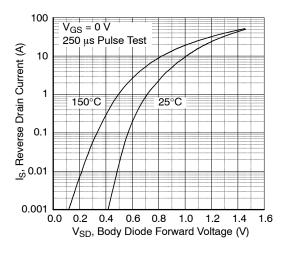


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

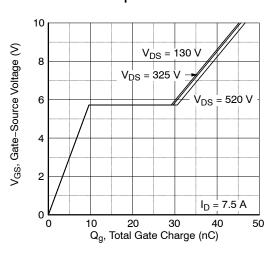


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

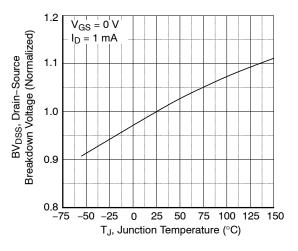


Figure 7. Breakdown Voltage Variation vs. Temperature

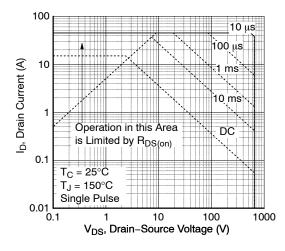


Figure 9. Maximum Safe Operating Area

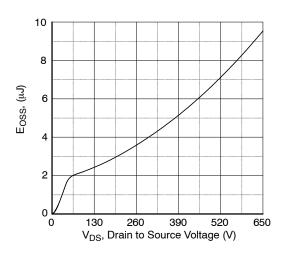


Figure 11. E_{OSS} vs. Drain to Source Voltage

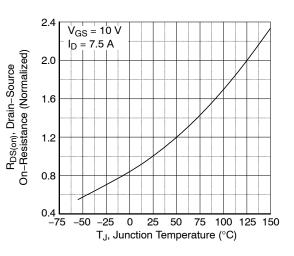


Figure 8. On–Resistance Variation vs. Temperature

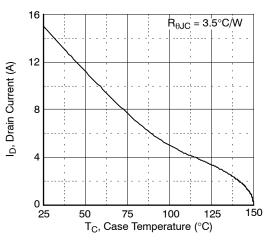


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

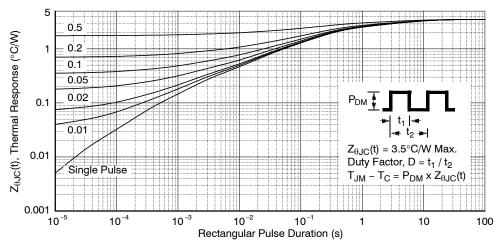


Figure 12. Transient Thermal Response Curve

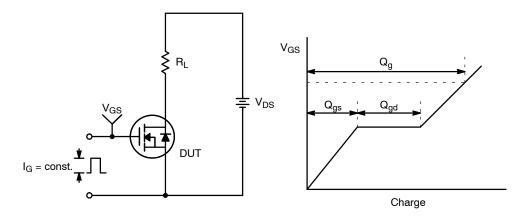


Figure 13. Gate Charge Test Circuit & Waveform

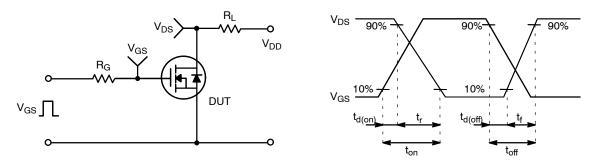


Figure 14. Resistive Switching Test Circuit & Waveforms

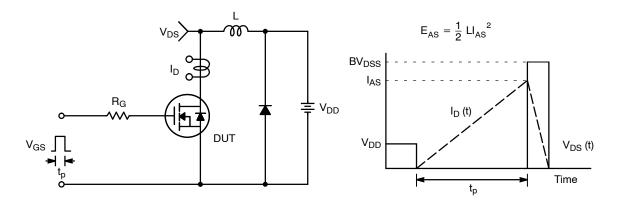


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

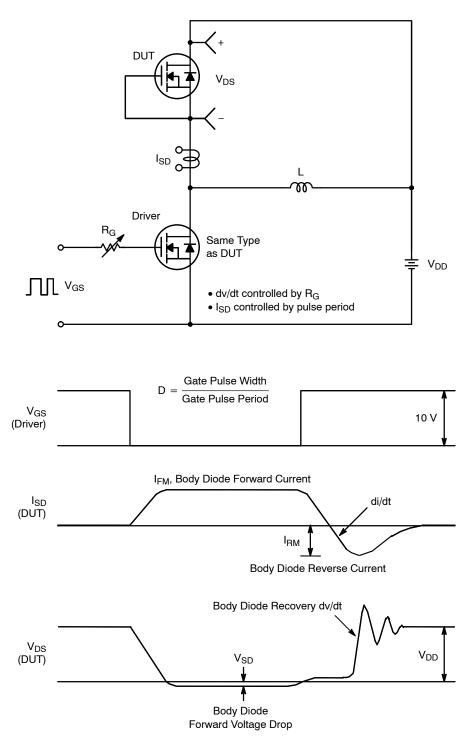
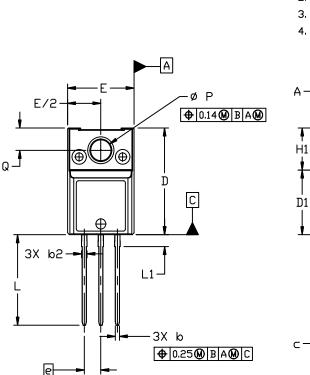


Figure 16. Peak Recovery dv/dt Test Circuit & Waveforms

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PACKAGE DIMENSIONS

TO-220 FULLPACK, 3-LEAD CASE 221BN ISSUE O



NDTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS

В

A1

A2

SEATING

NOTE 3

- 3. CONTOUR UNCONTROLLED IN THIS AREA.
- DIMENSIONS EXCLUDE BURRS, MOLD FLASH, AND TIE BAR PROTRUSIONS.

	MILLIMETERS			
DIM	MIN.	NDM.	MAX.	
Α	4.60	4.70	4.80	
A1	2.50	2.60	2.70	
A2	2.47	2.57	2.67	
b	0.56	0.63	0.69	
b2			0.90	
с	0.46	0.53	0.59	
D	15.80	16.00	16.20	
D1	9.58	9.68	9.78	
Е	10.00	10.20	10.40	
е	2.54 BSC			
H1	6.32 REF			
L	13.45	13.60	13.75	
L1	1.70	1.80	1.90	
Ρ	3.00	3.10	3.20	
Q	3.25	3.35	3.45	

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